TOSHIBA BI-DIRECTIONAL TRIODE THYRISTOR SILICON PLANAR TYPE

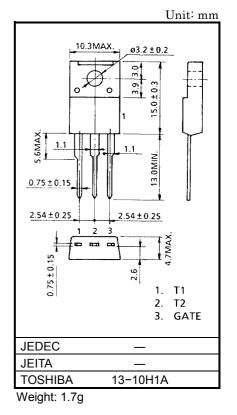
# SM16GZ47,SM16JZ47,SM16GZ47A,SM16JZ47A

AC POWER CONTROL APPLICATIONS

- Repetitive Peak Off-State Voltage : V<sub>DRM</sub> = 400, 600V
- R.M.S On–State Current
- : I<sub>T</sub> (RMS) = 16A
- High Commutating (dv / dt)
- Isolation Voltage : V<sub>ISOL</sub> = 1500V AC

#### **MAXIMUM RATINGS**

CHARACTER	ISTIC	SYMBOL	RATING	UNIT
Repetitive Peak	SM16GZ47 SM16GZ47A	V <sub>DRM</sub>	400	V
Off-State Voltage	SM16JZ47 SM16JZ47A	V DRM	600	v
R.M.S On-State Curren (Full Sine Waveform To		I <sub>T (RMS)</sub>	16	А
Peak One Cycle Surge On-State		<b>I</b>	150 (50Hz)	А
Current (Non-Repetitiv	e)	ITSM	165 (60Hz)	A
I <sup>2</sup> t Limit Value		l <sup>2</sup> t	112.5	A <sup>2</sup> s
Critical Rate of Rise of Current	On-State (Note 1)	di / dt	50	Α / μs
Peak Gate Power Dissi	pation	P <sub>GM</sub>	5	W
Average Gate Power D	issipation	P <sub>G (AV)</sub>	0.5	W
Peak Gate Voltage		V <sub>GM</sub>	10	V
Peak Gate Current		I <sub>GM</sub>	2	А
Junction Temperature		Тj	-40~125	°C
Storage Temperature F	Range	T <sub>stg</sub>	-40~125	°C
Isolation Voltage (AC, t	= 1 min.)	VISOL	1500	V



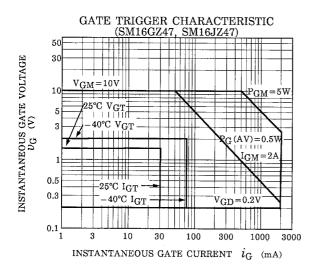
Note 1: di / dt Test condition  $V_{DRM} = 0.5 \times Rated$   $I_{TM} \le 25A$   $t_{gw} \ge 10\mu s$   $t_{gr} \le 250ns$  $i_{GP} = I_{GT} \times 2.0$ 

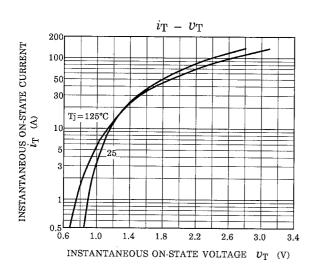
## ELECTRICAL CHARACTERISTICS (Ta = 25°C)

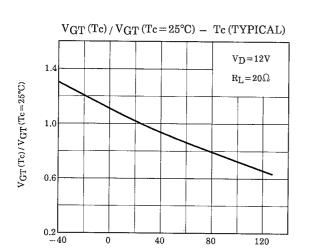
CHAF	RACTE	RISTIC		SYMBOL	TEST	CONDITION	MIN	TYP.	MAX	UNIT	
Repetitive Peak	Off−Sta	te Current		I <sub>DRM</sub>	RM V <sub>DRM</sub> = Rated		_	—	20	μA	
			Ι			T2 (+) , Gate (+)	_	_	1.5		
			П	N/	V <sub>D</sub> = 12V,	T2 (+) , Gate (−)		_	1.5	V	
Gate Trigger Volt	age		III	V <sub>GT</sub>	$R_L = 20\Omega$	T2 (-) , Gate (-)		_	1.5		
			IV			T2 (-) , Gate (+)		_	_		
			I			T2 (+) , Gate (+)	_	_	30		
	SM16	GZ47				T2 (+) , Gate (-)	_	_	30	- mA	
	SM16					T2 (-) , Gate (-)	_	_	30		
Gate Trigger			IV		V <sub>D</sub> = 12V,	T2 (-) , Gate (+)	_	_	_		
Current			I	I <sub>GT</sub>	$R_L = 20\Omega$	T2 (+) , Gate (+)	_	_	20		
	SM16	GZ47A	11			T2 (+) , Gate (-)	_	_	20		
	SM16	JZ47A				T2 (-) , Gate (-)	_	_	20		
	1	IV			T2 (-) , Gate (+)	_	_	_			
Peak On-State V	eak On-State Voltage			V <sub>TM</sub>	I <sub>TM</sub> = 25A		_	_	1.5	V	
Gate Non-Trigge	er Volta	ge		V <sub>GD</sub>	$V_{GD}$ $V_D$ = Rated, Tc = 125°C			_	_	– v	
Holding Current				I <sub>H</sub> V <sub>D</sub> = 12V, I <sub>TM</sub> = 1A				_	50	mA	
Thermal Resistance		R <sub>th (j−c)</sub>	Junction to Cas	se, AC		_	2.5	°C/W			
Critical Rate of R	ise of	SM16GZ4 <sup>-</sup> SM16JZ47		du / dt	v / dt V <sub>DRM</sub> = Rated, T <sub>j</sub> = 125°C Exponential Rise		_	300	_	V / μs 	
Off-State Voltage	е	SM16GZ4 <sup>-</sup> SM16JZ47		uv / ul			_	200	_		
Critical Rate of R		SM16GZ4 <sup>-</sup> SM16JZ47		(dv / dt) c V <sub>DRM</sub> = 400V, T <sub>i</sub> = 125°C 10 —		_	V / us				
Off-State Voltage Commutation	e at	SM16GZ4 <sup>-</sup> SM16JZ47		(dv / dt) c	(di / dt) c = - 8.7A / ms		4	_	_	V / µs	

### MARKING

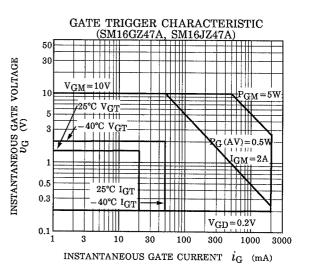
* NUMBEF	2	SYMBOL	MARK
* 1	Toshiba Product Ma	ark	5
* 2		SM16GZ47, SM16GZ47A	M16GZ47
2	TYPE	SM16JZ47, SM16JZ47A	M16JZ47
* 3		SM16GZ47A, SM16JZ47A	A
* 4		oth (Starting from Alphabet A) r (Last Decimal Digit of the Current Year)	Example 8A : January 1998 8B : February 1998 8L : December 1998

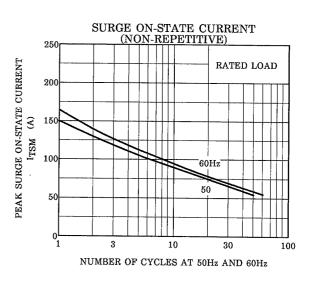


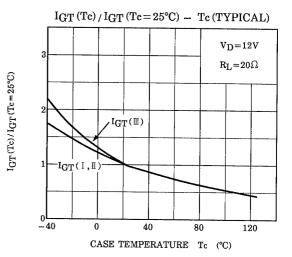


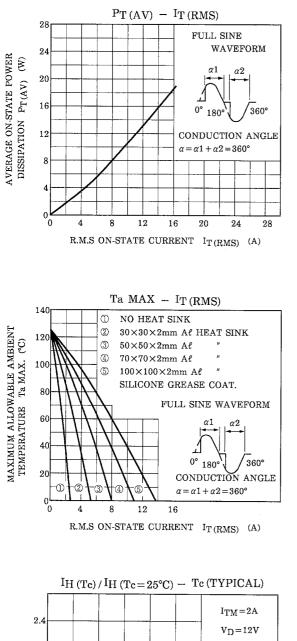


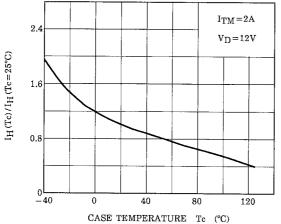
CASE TEMPERATURE Tc (°C)

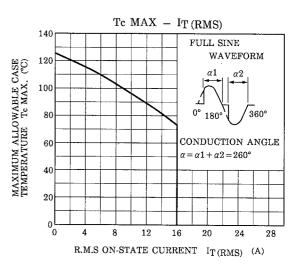


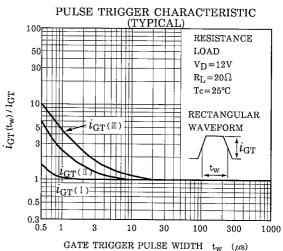


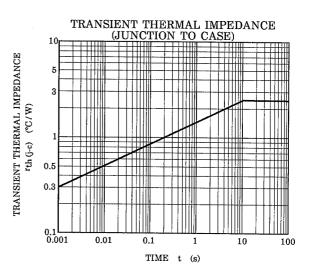












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